



UM2148

1K × 4 High Speed NMOS SRAM

Features

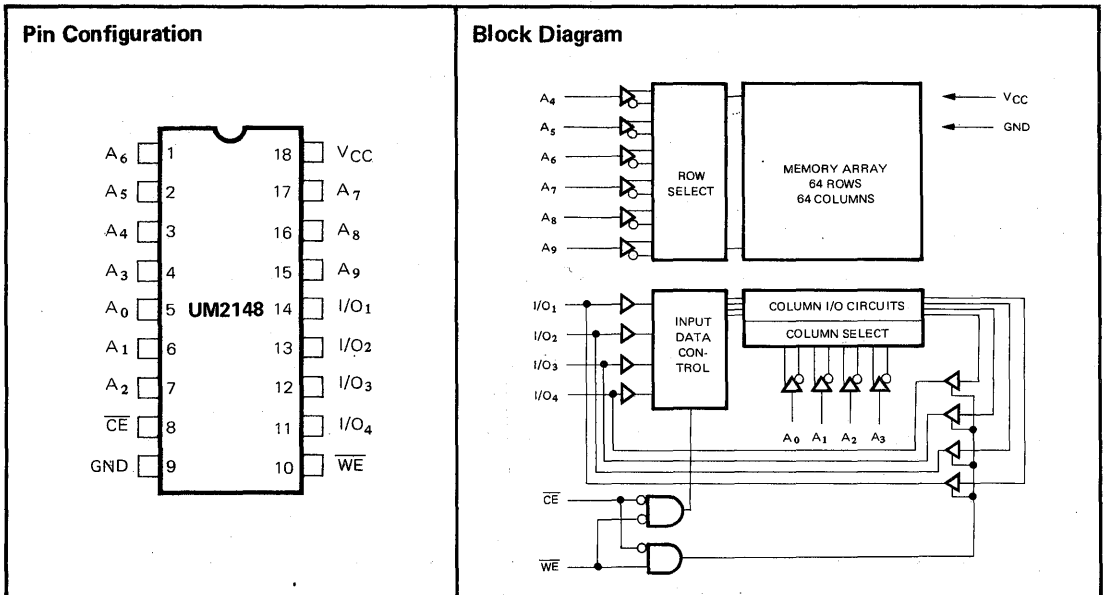
- 45 ns maximum access time
- No clocks or strobes required
- Automatic \overline{CE} power down
- Identical cycle and access times
- Single +5V supply ($\pm 10\%$)
- Pinout and function compatible to SY2148
- Industry standard 2114 pinout
- Totally TTL compatible all inputs and outputs
- Common data input and output
- High density 18-pin package
- Three-state output

General Description

The UMC UM2148 is a 4096-Bit Static Random Access Memory organized 1024 words by 4 bits and is fabricated using UMC's new scaled N-channel silicon gate technology. It is designed using fully static circuitry, therefore requiring no clock or refreshing to operate. Address set-up times are not required and the data is read out non-destructively with the same polarity as the input data. Common data input and output pins provide maximum design flexibility. The three-state output facilitates memory expansion by allowing the outputs to be OR-tied to other devices.

The UM2148 offers an automatic power down feature. Power down is controlled by the Chip Enable input. When Chip Enable (\overline{CE}) goes high, thus deselecting the UM2148 the device will automatically power down and remain in a standby power mode as long as \overline{CE} remains high. This unique feature provides system level power savings as much as 85%.

The UM2148 is packaged in an 18-pin DIP for the highest possible density. The device is fully TTL compatible and has a single +5V power supply.



Absolute Maximum Ratings*

Temperature Under Bias	-10°C to 85°C
Storage Temperature	-65°C to 150°C
Voltage on Any Pin with Respect to Ground	-3.5V to +7V
Power Dissipation	1.0W

***Comments**

Stresses above those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

D.C. Characteristics

($T_A = 0^\circ\text{C}$ to $+70^\circ\text{C}$, $V_{CC} = 5V \pm 10\%$ Unless otherwise specified) (note 8)

Symbol	Parameter	2148/-1/-2		2148L/L-1		Units	Conditions
		Min.	Max.	Min.	Max.		
I_{LI}	Input Load Current (All input pins)		10		10	μA	$V_{CC} = \text{Max}$, $V_{IN} = \text{Gnd to } V_{CC}$
$ I_{LO} $	Output Leakage Current		50		50	μA	$\overline{CE} = V_{IH}$, $V_{CC} = \text{Max}$ $V_{OUT} = \text{Gnd to } 4.5V$
I_{CC}	Power Supply Current		140		115	mA	$T_A = 25^\circ\text{C}$ $V_{CC} = \text{Max}$, $\overline{CE} = V_{IL}$
			150		125	mA	$T_A = 0^\circ\text{C}$ $V_{CC} = \text{Max}$, $\overline{CE} = V_{IL}$ Outputs Open
I_{SB}	Standby Current		30		20	mA	$V_{CC} = \text{Min to Max}$, $\overline{CE} = V_{IH}$
I_{PO}	Peak Power-on Current (Note 9)		50		30	mA	$V_{CC} = \text{Gnd to } V_{CC} \text{ Min}$ $\overline{CE} = \text{Lower of } V_{CC} \text{ or } V_{IH} \text{ Min}$
V_{IL}	Input Low Voltage	-3.0	0.8	-3.0	0.8	V	
V_{IH}	Input High Voltage	2.0	6.0	2.0	6.0	V	
V_{OL}	Output Low Voltage		0.4		0.4	V	$I_{OL} = 8\text{mA}$
V_{OH}	Output High Voltage	2.4		2.4		V	$I_{OH} = -4\text{mA}$

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Capacitance

($T_A = 25^\circ\text{C}$, $f = 1.0\text{ MHz}$)

Symbol	Test	Typ.	Max.	Unit
C_{OUT}	Output Capacitance		7	pF
C_{IN}	Input Capacitance		5	pF

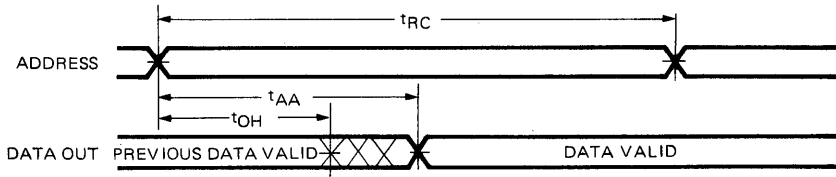
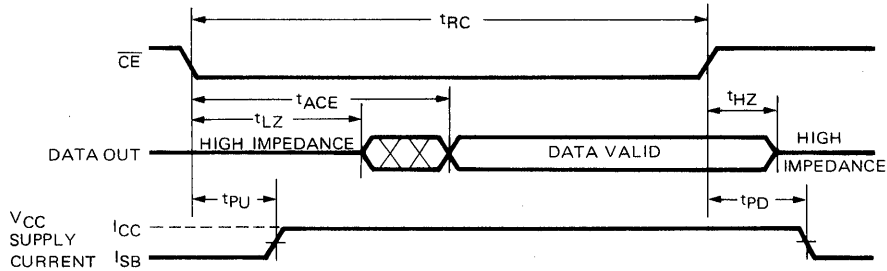
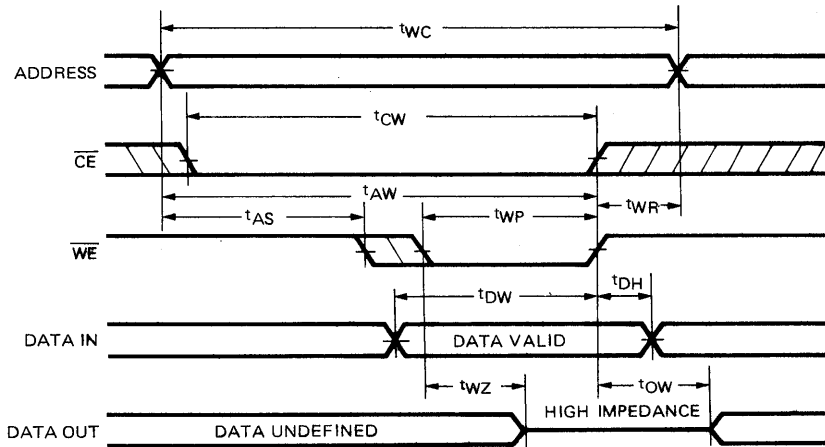
Note: This parameter is periodically sampled and not 100% tested.

A.C. Characteristics
 $(T_A = 0^\circ\text{C to } +70^\circ\text{C}, V_{CC} = 5\text{V } \pm 10\% \text{ Unless otherwise specified) (Note 8)}$
READ CYCLE

Symbol	Parameter	2148/L		2148-1/L-1		2148-2		Unit	Conditions
		Min.	Max.	Min.	Max.	Min.	Max.		
t_{RC}	Read Cycle Time	70		55		45		ns	
t_{AA}	Address Access Time		70		55		45	ns	
t_{ACE1}	Chip Enable Access Time		70		55		45	ns	Note 1
t_{ACE2}	Chip Enable Access Time		80		65		55	ns	Note 2
t_{OH}	Output Hold from Address Change	5		5		5		ns	
t_{LZ}	Chip Selection to Output in Low Z	10		10		10		ns	Note 7
t_{HZ}	Chip Deselection to Output in High Z	0	20	0	20	0	20	ns	Note 7
t_{PU}	Chip Selection to Power Up Time	0		0		0		ns	
t_{PD}	Chip Deselection to Power Down Time		30		30		30	ns	

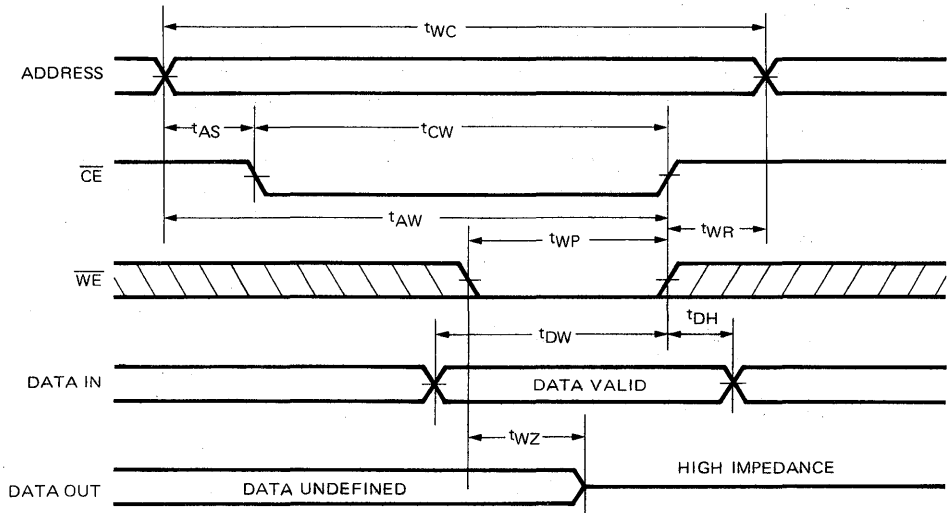
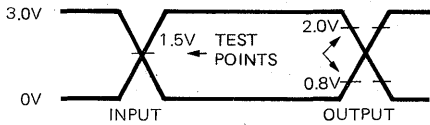
WRITE CYCLE

t_{WE}	Write Cycle Time	70		55		45		ns	
t_{CW}	Chip Enabled to End of Write	65		50		40		ns	
t_{AW}	Address Valid to End of Write	65		50		40		ns	
t_{AS}	Address Setup Time	0		0		0		ns	
t_{WP}	Write Pulse Width	50		40		35		ns	
t_{WR}	Write Recovery Time	5		5		5		ns	
t_{DW}	Data Valid to End of Write	25		20		20		ns	
t_{DH}	Data Hold Time	0		0		0		ns	
t_{WZ}	Write Enabled to Output in High Z	0	25	0	20	0	15	ns	Note 7
t_{OW}	Output Active from End of Write	0		0		0		ns	Note 7

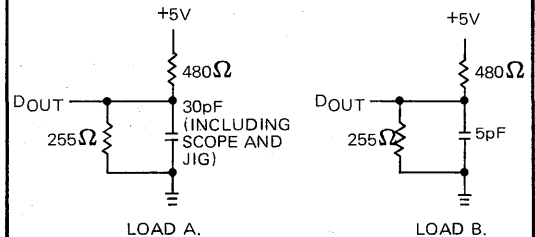
Timing Diagrams
READ CYCLE NO. 1 (NOTES 3 AND 4)

READ CYCLE NO. 2 (NOTES 3 AND 5)

WRITE CYCLE NO. 1 (WE CONTROLLED) (NOTE 6)

Notes:

1. Chip deselected for greater than 55ns prior to selection.
2. Chip deselected for a finite time that is less than 55ns prior to selection. (If the deselect time is 0ns, the chip is by definition selected and access occurs according to Read Cycle No. 1).
3. \overline{WE} is high for Read Cycles.
4. Device is continuously selected, $\overline{CE} = V_{IL}$.
5. Addresses valid prior to or coincident with \overline{CE} transition low.
6. If \overline{CE} goes high simultaneously with \overline{WE} high, the outputs remain in the high impedance state.
7. Transition is measured $\pm 500\text{mV}$ from low or high impedance voltage with load B. This parameter is sampled and not 100% tested.
8. The operating ambient temperature range is guaranteed with transverse air flow exceeding 400 linear feet per minute.
9. A pullup resistor to V_{CC} on the \overline{CE} input is required to keep the device deselected: otherwise, power-on current approaches I_{CC} active.
10. A minimum 0.5 ms time delay is required after application of V_{CC} (+5V) before proper device operation is achieved.

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WRITE CYCLE NO. 2 (CE CONTROLLED) (NOTE 6)

A.C. Testing Input, Output Waveform


A.C. TESTING: INPUTS ARE DRIVEN AT 3.0V FOR A LOGIC "1" AND 0.0V FOR A LOGIC "0". TIMING MEASUREMENTS ARE MADE AT 2.0V FOR A LOGIC "1" AND 0.8V FOR A LOGIC "0" AT THE OUTPUTS. THE INPUTS ARE MEASURED AT 1.5V. INPUT RISE AND FALL TIMES ARE 5 ns.

A.C. Testing Load Circuit

Ordering Information

Part Number	Access Time (Max.)	Operating Current (Max.)	Standby Current (Max.)	Package Type
UM2148	70 ns	150 mA	30 mA	Plastic
UM2148-1	55 ns	150 mA	30 mA	Plastic
UM2148-2	45 ns	150 mA	30 mA	Plastic
UM2148L	70 ns	125 mA	20 mA	Plastic
UM2148L-1	55 ns	125 mA	20 mA	Plastic